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APPLICANT  
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## U.S. PATENT DOCUMENTS

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FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Code - Number - Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation	
						Yes	No
		EP 1 648 023 A1	4/19/2006	SUMITOMO HEAVY INDUSTRIES LTD		X	

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	
		European Supplementary Search Report, with Written Opinion, issued in European Patent Application No. EP 04773759.8/1672683 dated on September 2, 2008	
		ITO et al " 10-15nm Ultrashallow Junction Formation byFlash-Lamp Annealing" pages 2394-2398 Japanese Journal of Applied Physics, Tokyo, Japan Vol. 41, No. 4b September 26, 2001	

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